

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of

KEREN et al.

Atty. Ref.: 4110-2

Serial No. To Be Assigned

Group: Not Yet Assigned

Filed: December 27, 2001

Examiner: Not Yet Assigned

For: METHOD AND APPARATUS FOR TESTING AND MAPPING PHASE OBJECTS

\* \* \* \* \*

December 27, 2001

Assistant Commissioner for Patents  
Washington, DC 20231

Sir:

**PRELIMINARY AMENDMENT**

Please amend the above-identified application as follows:

**IN THE CLAIMS**

Please substitute the following amended claims for corresponding claims previously presented. A copy of the amended claims showing current revisions is attached.

a' 7. (Amended) A method according to claim 1, wherein the calculation of the optical parameter of interest comprises transforming the recorded moiré pattern into one or more points in the spatial frequency plane, such that the vectors defining said points are the vectors of spatial frequencies  $V_y$  and  $V_x$  associated with said moiré pattern, identifying the components of said vectors ( $V_{yx}$ ,  $V_{yy}$ ) and ( $V_{xx}$ ,  $V_{xy}$ ) and substituting their values in an equation which linearly

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